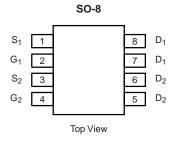


# IRF7328TRPBF-VB Datasheet **Dual P-Channel 30-V (D-S) MOSFET**

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A) <sup>d, e</sup>	Q <sub>g</sub> (Typ.)			
- 30	0.021 at V <sub>GS</sub> = - 10 V	- 8.0	15 nC			
- 30	0.028 at V <sub>GS</sub> = - 4.5 V	- 7.0	13110			



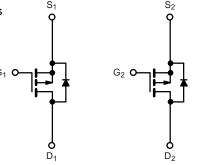
#### **FEATURES**

- · Halogen-free
- Trench Power MOSFET
- 100 % UIS Tested

### **APPLICATIONS**

- · Load Switches
  - Notebook PCs
  - Desktop PCs





P-Channel MOSFET

P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b>	$_{A}$ = 25 °C, unless other	erwise noted		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	- 30	V	
Gate-Source Voltage	V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		- 9.5 <sup>e</sup>	
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C		- 8.0 <sup>e</sup>	
Continuous Diain Current (1) = 130 C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	- 8.3 <sup>a, b</sup>	
	T <sub>A</sub> = 70 °C		- 7.9 <sup>a, b</sup>	A
Pulsed Drain Current	I <sub>DM</sub>	- 32 <sup>e</sup>		
0 " 0 0 0 0	T <sub>C</sub> = 25 °C	1-	- 4.1	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	ls –	- 2.0 <sup>a, b</sup>	
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	- 20	
Single-Pulse Avalanche Energy	L = 0.1 mn	E <sub>AS</sub>	20	mJ
	T <sub>C</sub> = 25 °C		5.0	
Maximum Dawar Dissination	T <sub>C</sub> = 70 °C	ь.	3.2	W
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.5 <sup>a, b</sup>	VV
	T <sub>A</sub> = 70 °C		1.6 <sup>a, b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	38	50	°C/W	
Maximum Junction-to-Foot	Steady State	$R_{thJF}$	20	25	C/VV	

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 85 °C/W.
- d. Based on  $T_C$  = 25 °C.
- e. Limited by package.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 31		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.5		mv/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 3.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zoro Coto Voltago Proin Current	lasa	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V			- 1	<u>—</u> иА	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
Davis Ossans Os Otata Basista sa	D	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 7.3 A		0.021			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 6.2 A		0.028		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 9.1 A		23		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			1350		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		215			
Reverse Transfer Capacitance	C <sub>rss</sub>	1		185			
Total Cata Charres	$Q_g$ $V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -9.1 \text{ A}$	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -9.1 \text{ A}$		32	50		
Total Gate Charge			15	25	1		
Gate-Source Charge	$Q_gs$	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -9.1 \text{ A}$		4		nC	
Gate-Drain Charge	Q <sub>gd</sub>	1		7.5			
Gate Resistance	R <sub>g</sub>	f = 1 MHz		5.8		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			10	15		
Rise Time	t <sub>r</sub>	$V_{DD} = -15 \text{ V}, R_{L} = 15 \Omega$		8	15		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong$ - 1 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		45	70		
Fall Time	t <sub>f</sub>	]		12	25		
Turn-On Delay Time	t <sub>d(on)</sub>			42	70	ns	
Rise Time	ì,	$V_{DD} = -15 \text{ V}, R_{L} = 15 \Omega$		35	60		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong$ - 1 A, $V_{GEN}$ = - 4.5 V, $R_g$ = 1 $\Omega$		40	70		
Fall Time	t <sub>f</sub>	]		16	30		
<b>Drain-Source Body Diode Characterist</b>	ics				•		
Continous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 4.1	_	
Pulse Diode Forward Current	I <sub>SM</sub>	-			- 32	Α	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = -2 A, V <sub>GS</sub> = 0 V		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			34	60	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1	A / T 05 00	22	40	nC	
everse Recovery Fall Time $t_a$ $I_F = -2 \text{ A, dl/dt} = 100 \text{ A/µs, T}_J = 0$		$I_F = -2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		11			
Reverse Recovery Rise Time	t <sub>b</sub>	1		23		ns	

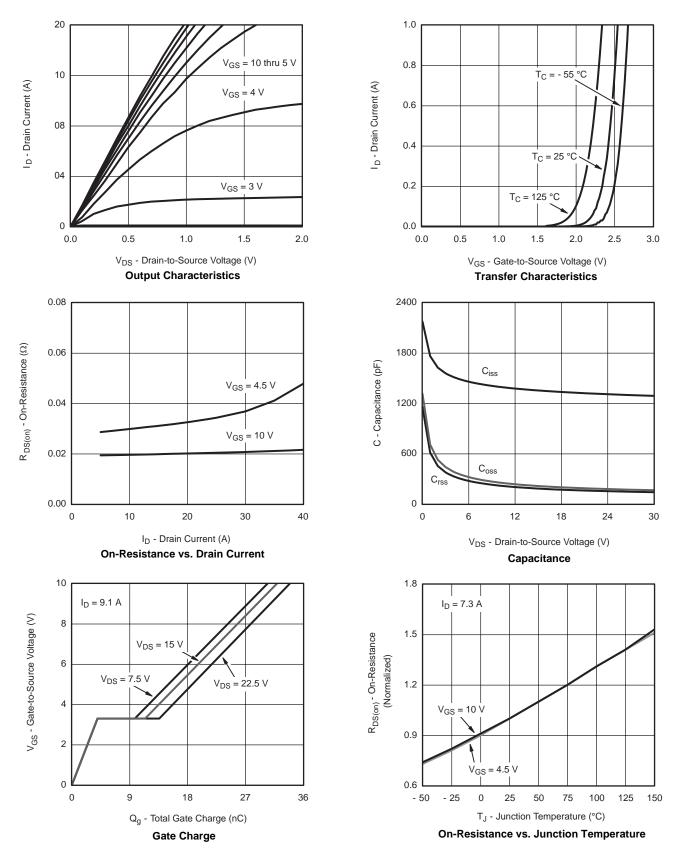
#### Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

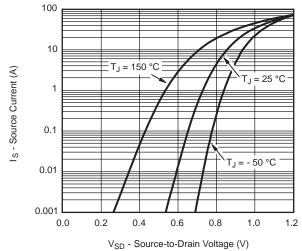
a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

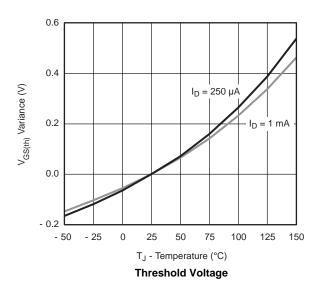






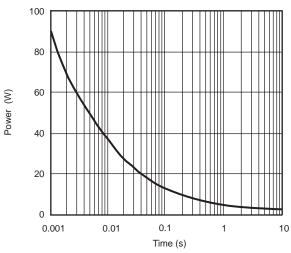


#### Source-Drain Diode Forward Voltage

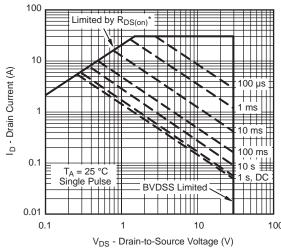


 $C_{\text{O}} = 0.10$   $C_{\text{O}} = 0.08$   $C_{\text{O}} = 0.08$   $C_{\text{O}} = 0.08$   $C_{\text{O}} = 0.04$   $C_{\text{O}} =$ 

On-Resistance vs. Gate-to-Source Voltage



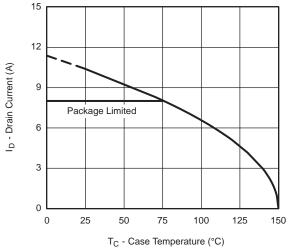
Single Pulse Power, Junction-to-Ambient



\* V<sub>GS</sub> > minimum V<sub>GS</sub> at which R<sub>DS(on)</sub> is specified

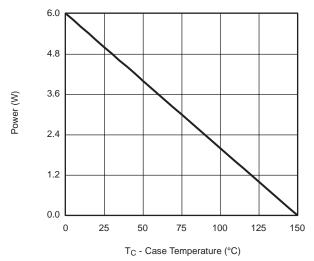
Safe Operating Area

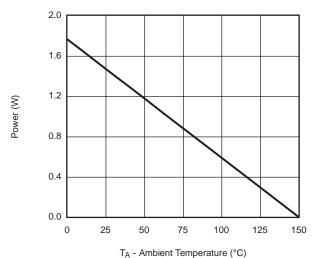




Current Deretines\*



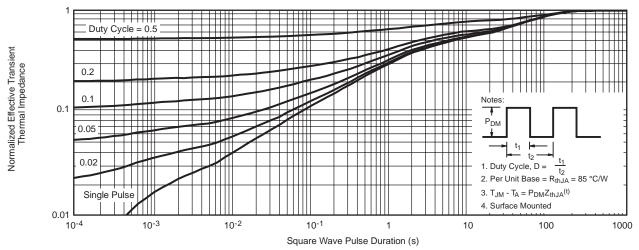




Power, Junction-to-Foot Power Derating, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





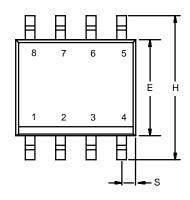
Normalized Thermal Transient Impedance, Junction-to-Ambient

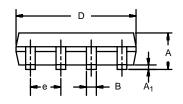


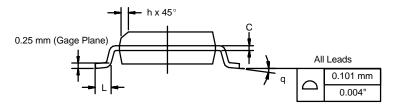
Normalized Thermal Transient Impedance, Junction-to-Foot



**SOIC (NARROW): 8-LEAD**JEDEC Part Number: MS-012







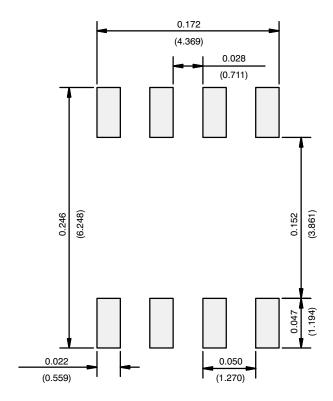
	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A <sub>1</sub>	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	) BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Poy I 11-Sep-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



## **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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